Hironori Yoshioka

List of Publications by Year in descending order

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25 papers

535 citations

1051969 10 h-index 799663 21 g-index

26 all docs

26 docs citations

times ranked

26

452 citing authors

#	Article	IF	Citations
1	Determination of the interface between amorphous insulator and crystalline 4H–SiC in transmission electron microscope image by using convolutional neural network. AIP Advances, 2021, 11, 015101.	0.6	1
2	Theoretical investigation of the interface fluctuation causing low channel conductivity at SiO2/SiC interfaces through the self-energy and average Green's function. AIP Advances, 2019, 9, 075306.	0.6	7
3	Characterization of SiO2/SiC interface states and channel mobility from MOSFET characteristics including variable-range hopping at cryogenic temperature. AIP Advances, 2018, 8, .	0.6	16
4	(Invited) Interface Defects in C-face 4H-SiC MOSFETs: An Electrically-Detected-Magnetic-Resonance Study. ECS Transactions, 2017, 80, 147-153.	0.3	6
5	Reduction of interface states by hydrogen treatment at the aluminum oxide/4H-SiC Si-face interface. AIP Advances, 2016, 6, .	0.6	15
6	N-channel field-effect mobility inversely proportional to the interface state density at the conduction band edges of SiO2/4H-SiC interfaces. AIP Advances, 2015, 5, .	0.6	57
7	Characterization of Interface State Density from Subthreshold Slope of MOSFETs at Low Temperatures (≥ 10 K). Materials Science Forum, 2015, 821-823, 745-748.	0.3	1
8	Accurate Characterization of Interface State Density of SiC MOS Structures and the Impacts on Channel Mobility. Materials Science Forum, 2014, 778-780, 418-423.	0.3	5
9	Effects of interface state density on 4H-SiC n-channel field-effect mobility. Applied Physics Letters, 2014, 104, 083516.	1.5	35
10	Characterization of very fast states in the vicinity of the conduction band edge at the SiO2/SiC interface by low temperature conductance measurements. Journal of Applied Physics, 2014, 115, .	1.1	32
11	Physics of SiC MOS interface and development of trench MOSFETs. , 2013, , .		14
12	Generation of very fast states by nitridation of the SiO2/SiC interface. Journal of Applied Physics, 2012, 112, .	1.1	140
13	Accurate evaluation of interface state density in SiC metal-oxide-semiconductor structures using surface potential based on depletion capacitance. Journal of Applied Physics, 2012, 111, .	1.1	112
14	Bandgap shift by quantum confinement effect in $\tilde{a} \in 100\tilde{a} \in \infty$. Si-nanowires derived from threshold-voltage shift of fabricated metal-oxide-semiconductor field effect transistors and theoretical calculations. Journal of Applied Physics, 2011, 109, 064312.	1.1	6
15	Quantum-confinement effect on holes in silicon nanowires: Relationship between wave function and band structure. Journal of Applied Physics, 2011, 109, 064318.	1.1	16
16	Tight-binding study of size and geometric effects on hole effective mass of silicon nanowires. , 2010, , .		0
17	Mobility oscillation by one-dimensional quantum confinement in Si-nanowire metal-oxide-semiconductor field effect transistors. Journal of Applied Physics, 2009, 106, 034312.	1.1	10
18	Enhanced Drain Current of 4H-SiC MOSFETs by Adopting a Three-Dimensional Gate Structure. IEEE Transactions on Electron Devices, 2009, 56, 2632-2637.	1.6	12

#	Article	IF	CITATIONS
19	Fabrication and Electronic Characteristics of Silicon Nanowire MOSFETs. Materials Research Society Symposia Proceedings, 2008, 1080, 1.	0.1	0
20	High Breakdown Voltage (<tex>\$â%«\$</tex> 1000 V) Semi-Superjunction MOSFETs Using 600-V Class Superjunction MOSFET Process. IEEE Transactions on Electron Devices, 2005, 52, 2317-2322.	1.6	35
21	Field-induced magnetic transitions of exchange competing system GdMn2Ge2. Journal of Magnetism and Magnetic Materials, 2004, 272-276, 591-592.	1.0	0
22	Novel Field-induced Magnetic Transitions of GdMn2Ge2. Journal of the Physical Society of Japan, 2003, 72, 3197-3203.	0.7	2
23	Novel magnetic phase transitions and magnetoresistance of GdMn2Ge2. Journal of Physics Condensed Matter, 2002, 14, L687-L693.	0.7	7
24	Plastic deformation of single crystals with the C11b structure: Effect of the c/a axial ratio. Materials Research Society Symposia Proceedings, 2000, 646, 62.	0.1	1
25	Improved On-Current of 4H-SiC MOSFETs with a Three-Dimensional Gate Structure. Materials Science Forum, 0, 615-617, 753-756.	0.3	0